

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	JEOL	FE-EPMA	JXA-8530F	2017	<ul style="list-style-type: none"> <li>•JXA-8530F(5ch) Plus</li> <li>•EPMA Data processor</li> <li>•Phase analysis program</li> <li>•Irregular sample analysis program</li> <li>•Trace element analysis program</li> <li>•Phase map Maker</li> <li>•Liquid nitrogen trap</li> <li>•Chiller</li> <li>•Active Vibration removal stand</li> </ul>	
2	JEOL	SEM	JSM-6510LV	2014	<ul style="list-style-type: none"> <li>•JSM-6510LV</li> <li>•EDS AMETEK EDAX Octane Pro</li> <li>•Operation Keyboard</li> <li>•Motor Controlled Stage(2 Axis)</li> </ul>	
3	JEOL	SEM	JSM-6360LV	2004	<ul style="list-style-type: none"> <li>•JSM-6360LV SEM main unit</li> <li>•EDAX G-XM2 CDU/SUTW</li> <li>•61090(MS) 2-axis motor stage(Max specimen size 150 mm, 80x40mm)</li> <li>•47414 PC unit(2 USB port, PC card slot)</li> <li>•34470 backscatter electron detector</li> <li>•47512 CRT monitor</li> <li>•65020(PRD2) device for photography</li> <li>•65040(CSI2) device for scan Image photography</li> <li>•65150(OKB) operation keyboard</li> <li>•49020 chiller</li> <li>•LGSHL solvent holder</li> </ul>	
4	Keyence	3D Surface Measurement Microscope	VE-9800S	2006	with 3D/Motorized Stage EDAX G-XM2 CDU/SUTW	

5	Olympus	Semiconductor wafer inspection microscope	2006	<ul style="list-style-type: none"> <li>•Brightfield/Darkfield illuminator+Fiber Adapter(BX-RLA2+U-LGAD)</li> <li>•Motorized Nosepiece 6-Position RMS Threads(ob: 1.25x 2.5x 10x 20x 50x 100xBD)(U-D6REM)</li> <li>•Levo Controller/Hand switch(U-REMCB/U-HSTR)</li> <li>•Light Guide</li> <li>•Transmission Light unit</li> <li>•Imaging lens(Camera adapter)/touble port(U-TLU+U-TV0.5XC)</li> <li>•Light Reduction Filter/Color Temperature Conversion Filter</li> <li>•Color camera(Including the manual measurement function)</li> <li>•Stage and stage driving controller</li> <li>•Color video printers and ACC</li> <li>•Auto focus unit and PC</li> </ul>	
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**Price is being negotiated (not secured/매입 검토중)**

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	Hitachi	FIB-SEM	NX2000	2017	Automatic u-S system, MGS II3 reservoir (C, W, Pt), Ar lens barrel multiple gas type compatible system, Swing system, Micro-sampling system MPS-IV (4 axes), Doble tilting system, Sample holder for 200mm wafer, Sample table for vertical and horizontal TEM processing, Continuous A-TEM II, Chiller	
2	Hitachi	SEM	S-3700N	2017	SEM, Large sample chamber (maximum 300mm diameter), 5-axis MD, Camera navigation, Secondary electron/Reflective electron, Low-vacuum secondary electron detector ESED-II, EDX HORIBA EMAX Evolution X Max50 EX470	
3	JEOL	SEM	JSM-IT500HR/LA	2019	SEM, Maximum sample size 200mm diameter, High-luminance electron gun, High/Low vacuum mode, Secondary electron/reflection electron detector, 5 axis motor stage, Stage navigation, EDX Other.	Upcoming in Apr.
4	Hitachi	SEM	SU3500	2016	SEM, Secondary electron detector, Reflection electron detector, Low-vacuum secondary electron detector, EDX (American Tech Octane Plus), MC1000 ion sputtering, Etc.	
5	Hitachi	SEM	S-3400N	2011	SEM, Type 1, Secondary electron detector, reflection electron detector, Maximum sample size 200mm×35mm thickness, Turbo-molecular pump	
6	Mitutoyo	CNC Measuring System	QV-A808P8L-D	2021	Color camera, 4 turret, objective QV-HR2.5/5/10x, measuring range 800x800x150mm, minimum display 0.1μm, External dimensions 1475Wx1860Dx1578Hmm, mass approximately 2600kg	
7	Shimadzu	Microfocus X-Ray CT System	inspeX io SMX225CT FPD HR	2019	FPD-16, 8CL-H, Data processing system, Image analysis software, Subworkstations, Etc.	

8	Shimadzu	Microfocus X-Ray CT System	inspe X io SMX-100CT	2013	VGMAX Material Pack, Analysis of VGMAX defect inclusions, Fiber orientation analysis, Coordinate measurement
9	Leica	Stereo Microscope	M80	2017	M80, Object lens Plan 1.0x, LED ring light lighting, Binocular tilt lens barrel 45 degrees, Eyepiece 10x (x2), Ergo wedge, Photo tube, Digital camera MC170HD, C-mount, Flex Arm, Monitor 15.6"

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